CLAIMS

1. An electrical contact for use in an integrated circuit testing apparatus, comprising:

a rigid bottom member (10) having two planar surfaces (12, 14), said bottom member formed of an electrically conductive material, and said two planar surfaces (12, 14) sloping towards each other at an angle of between 5° and 20° to the vertical;

a flexible top member (20) having two arms (22, 24) extending over said bottom member (10), said two arms having an inwards bias such that an inner surface (23, 25) of each said arm is pressed in contact with each said planar surface (12, 14), so that as the top member (20) is lowered towards the bottom member (10), the two arms (22, 24) of the top member flex outwards, and maintain an inward pressure on the said planar surfaces (12, 14) of said bottom member (10), and the said top member formed of an electrically conductive material; and

a compressible member (30) located between a top end (16) of said bottom member (10) and a bifurcation inner surface (26) of said top member (20), said compressible member exerting an outward force on said two arms (22, 24) when compressed.

2. An electrical contact for use in an integrated circuit testing apparatus according to claim 1, wherein the said compressible member (30) has a cylindrical shape, and the said top end (16) of said bottom member (10) is adapted to match and receive the said compressible member (30).

3. An electrical contact for use in an integrated circuit testing apparatus according to claim 2, wherein the said bifurcation inner surface (26) of

said top member (20) is adapted to match and receive the said compressible member (30).